

Advanced Topic in MEMS (06-88-552-01-2016W)

Non-contact type RF MEMS Switch for Radar applications

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Introduction

- ✓ IoT is expected to reach trillions of dollars by 2020.
- ✓ Where size of the device plays an important role in many applications.
- ✓ Micro ElectroMechanical Systems (MEMS) is gaining tremendous popularity in IoT.
- ✓ Our project deals with the design of MEMS switches.



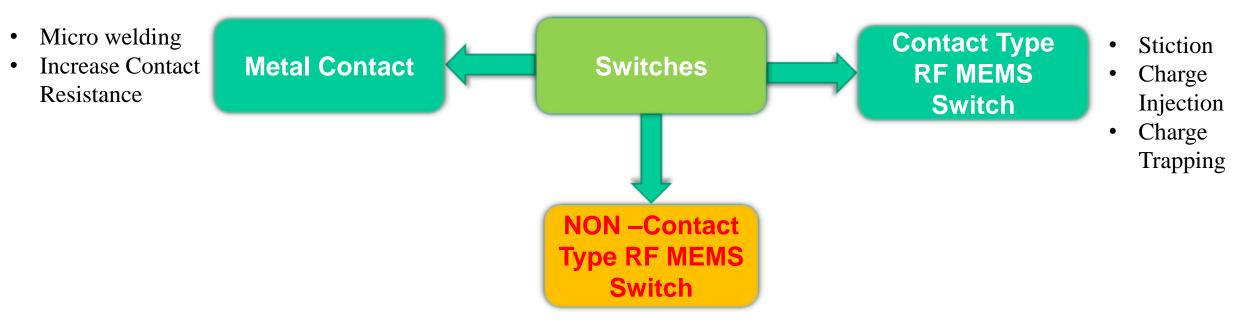


Comparison of Switches

Characteristic	PIN diode (IN4001)	FET (BF862)	MEMS SWITCH
Area	50mm	1.1mm	0.9mm
Resistance	1-5Ω	1-5Ω	0.5Ω
Insertion Loss (dB)	0.7	0.8	0.29
Isolation (dB)	15	20	30.1
Power Consumption	Low	Low	VERY LOW



Switches



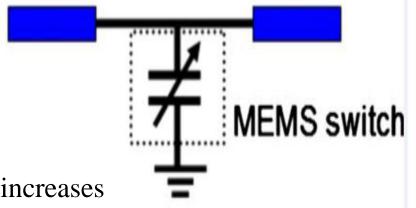
Variable capacitor structures containing small air gap



Principle Of Operation

ON State

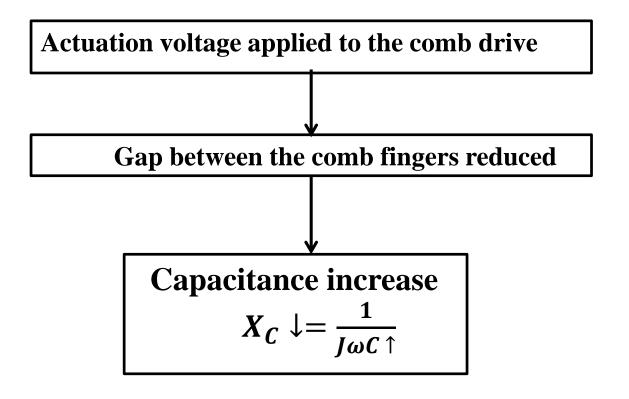
In ON state, when variable capacitors are not actuated, input signal passes from input port to output port

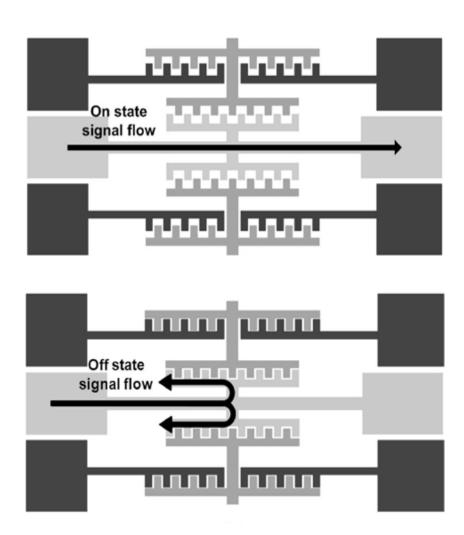


OFF State

In OFF state, When actuation voltage is applied capacitance increases providing a low impedance RF path to the ground. This prevents the signal to reach the output port.



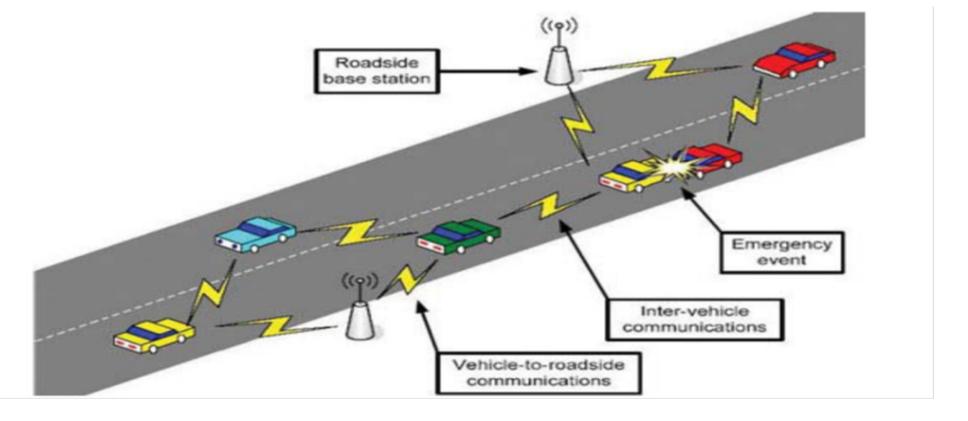






Target Application

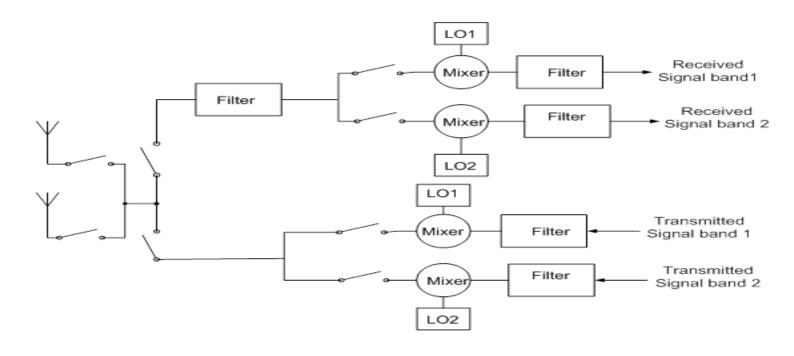
- Our project application deal's with <u>24GHz</u> frequency which has allocated a band name of super high frequency (**K band**), which mainly finds application in Radars.
- Our switch design finds its application in intelligent transportation system.





Communication Between Road Side Base station and Vehicles

MEMS switches can be used in base station to increase reliability



Base Station Tx/Rx block diagram



Mathematical Modeling

ON State

 $Z_{in} = Z_{out}$ Impedance matching (Maximum signal transfer)

$$j\omega L_{1} + \frac{(j\omega L_{1} + Z_{0})(J\omega L_{eq} + \frac{1}{j\omega C_{eq}})}{j\omega (L_{1} + L_{eq}) + \frac{1}{j\omega C_{eq}} + 50} = 50$$
 (1)

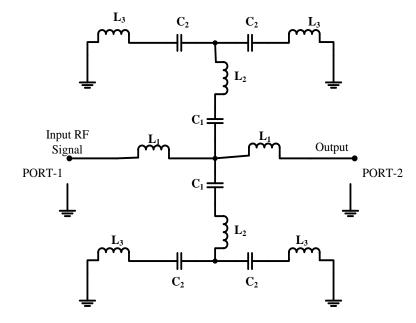
$$-2\omega^{2}L_{1}L_{eq} + \frac{2L_{1}}{C_{eq}} - \omega^{2}L_{1}^{2} = 2500$$
 (2)

Where,

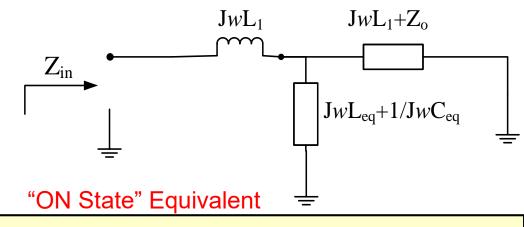
$$L_{eq} = \frac{1}{2}L_2 + \frac{1}{4}L_3$$

$$C_{eq} = \frac{4C_1C_2}{C_1 + 2C_2}$$

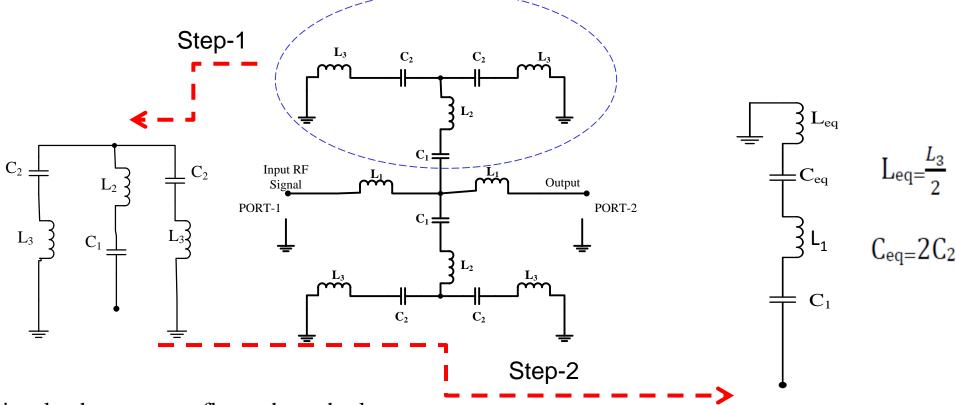
$$C_{\text{eq}} = \frac{4C_1C_2}{C_1 + 2C_2}$$



Lumped Circuit model







During OFF state, signal chooses to flow through low impedance path (two symmetrical parts) one of which is highlighted in the

$$j\omega(L_{eq} + L_2) + \frac{1}{j\omega(C_{eq} + C_1)} = 0$$
 (3)

$$\frac{C_1 + 2C_2}{C_1 C_2 (L_3 + 2L_2)} = 2.27395 * 10^{22}$$
 (4)



Mathematical Modeling

ON State

OFF state

$$-2\omega^2 L_1 L_{eq} + \frac{2L_1}{C_{eq}} - \omega^2 L_1^2 = 2500$$
 (5)

$$\frac{C_1 + 2C_2}{C_1 C_2 (L_3 + 2L_2)} = 2.27395 * 10^{22}$$
 (6)

Parameter	ON State	OFF State
L1	0.19nH	0.19nH
L2	0.22nH	0.19nH
L3	0.19nH	0.19nH
C1	43.1fF	366fF
C2	130fF	158fF



S –Parameters

<u>Insertion Loss</u>: When the switch is in ON state. It is expected that the entire signal flows from port 1 to port 2. But in reality a part of the signal is lost. This loss is termed as insertion loss.

Transmission Coefficient = $\frac{C}{A} = S_{21}$

 S_{21} in decibels = $20log(S_{21})$

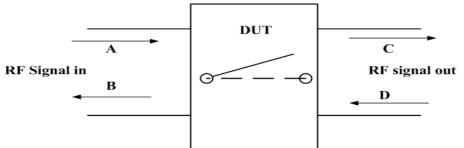
Insertion loss = $-20log(S_{21})$

Isolation Loss: When the switch is in OFF state. It is expected that no signal flows from port 1 to port 2. But in reality a part of the signal is transmitted. This loss is termed as isolation loss.

Transmission Coefficient = $\frac{c}{A} = S_{21}$

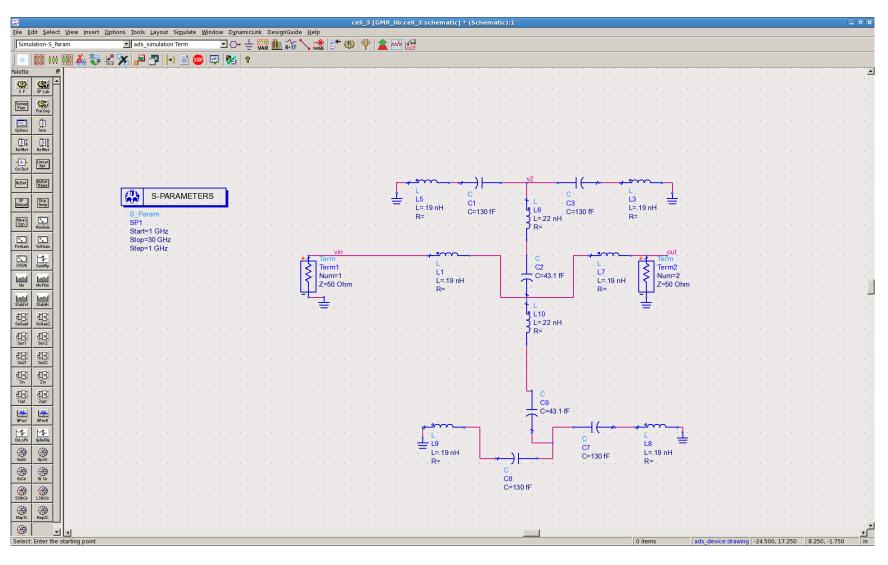
 S_{21} in decibels = $20log(S_{21})$

Isolation loss = $-20log(S_{21})$



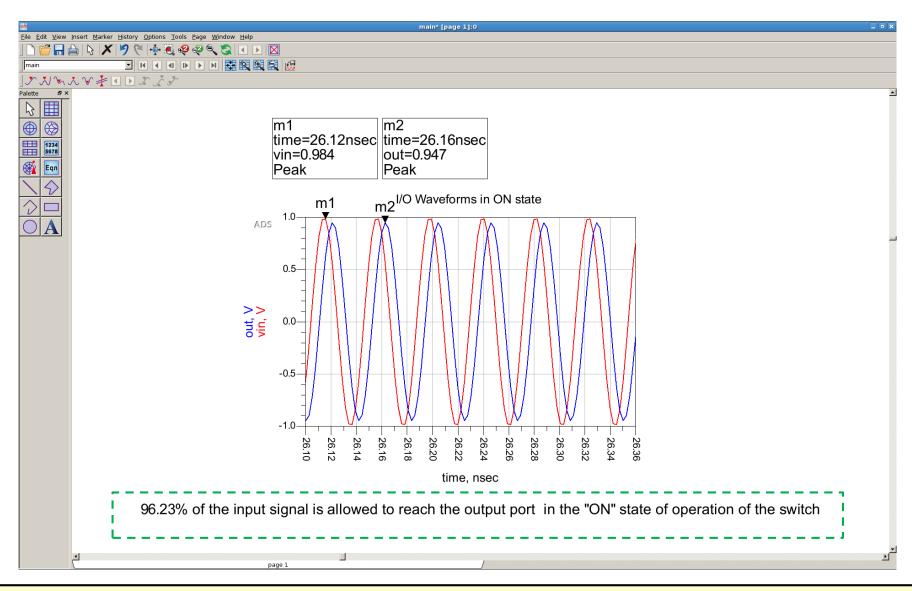


ON STATE



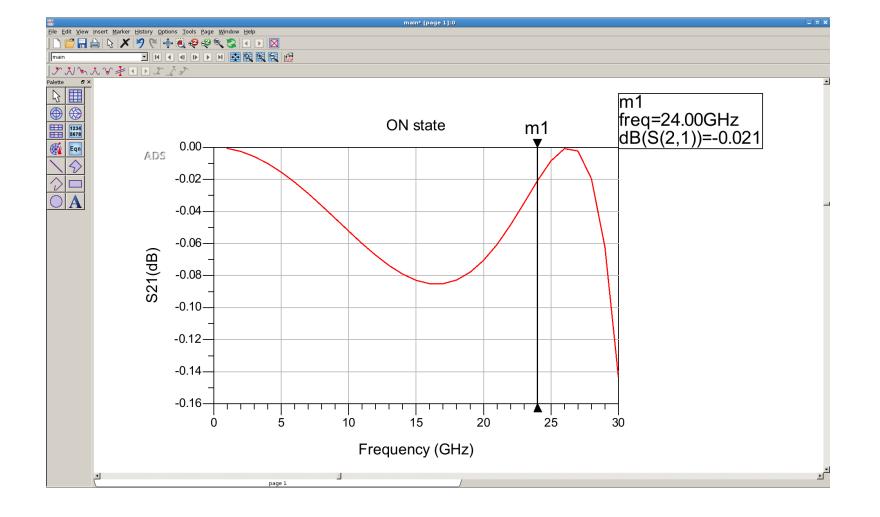


ON State

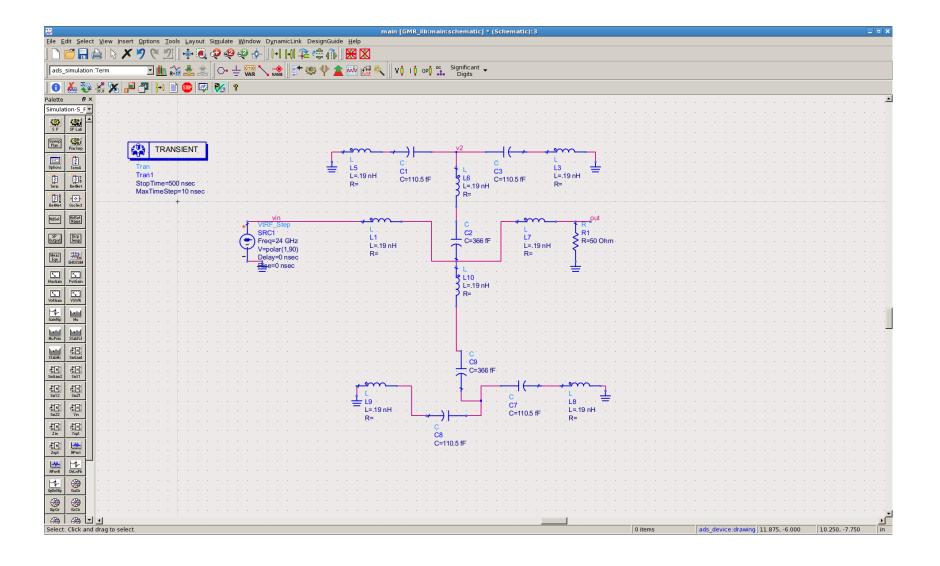




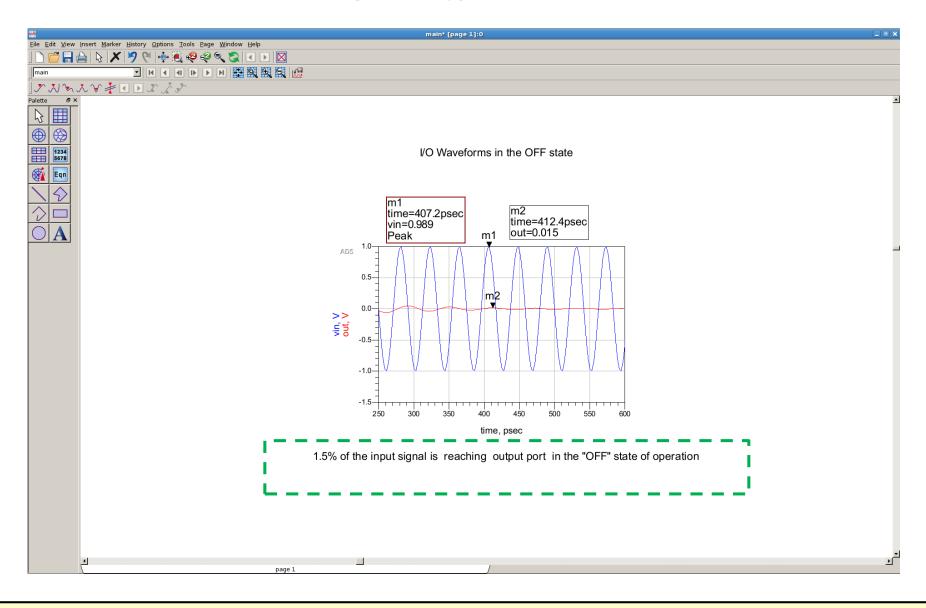
ON STATE



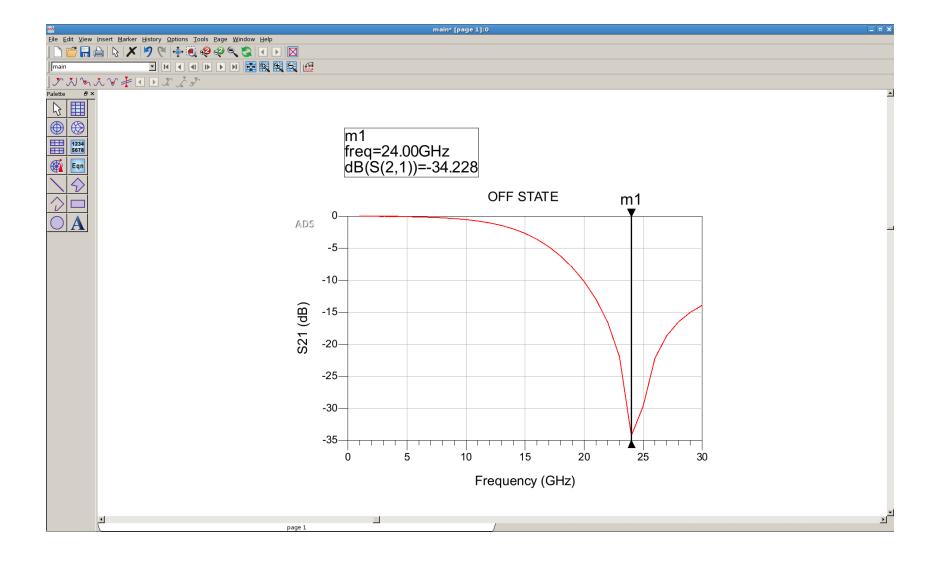














Target design specifications

Switch size	•	1.1mm × 0.9 mm	
CPW line wid	ith	40µm	
CPW line len	gth	780 µm	
Characteristic imp	edance	50Ω	
Comb finger length		C1	24 µm
Comb imger ie	ngui	C2	37 μm
Comb finger Width		C1	2 µm
		C2	2 µm
Comb finger thickness		40 μm	
Air gap between comb fingers		C1	1.5 µm
		C2	3 µm
Air gap between substrate and Switch		30 μm	
Frequency		24GHz	
Anchor Size		30 μm	
Substrate height		101.3 μm	
Folded Flexure beam	L	357µm	
	W	5 μm	
	t	40 μm	



Comb drive actuator design (C1)

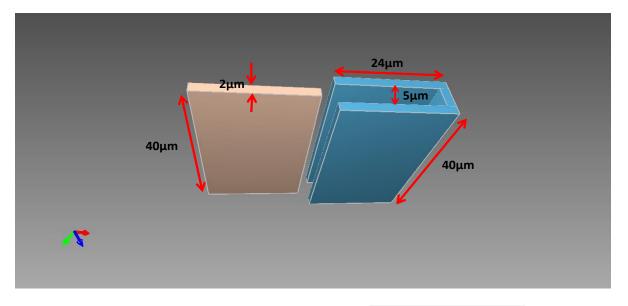
 Capacitance between two metal plates with one stator and one rotor is given as:

$$C = \frac{2n\varepsilon t(y + y_0)}{g}$$

• So for Capacitor C1 having overlap gap (y) of 7µm and gap (g) between fingers is 1.5µm and thickness (t) is 40µm with 110 comb fingers in rotor side, the capacitance obtained was 366fF (OFF state).

$$C1 = 366fF$$

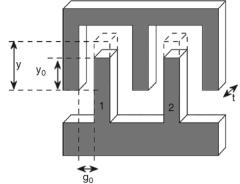
 $220C1 = 366fF$
 $C1 = 1.66fF$ for each finger (OFF state)



$$C1 = 43.1 fF$$

 $220C1 = 43.1 fF$

$$C1 = 0.1959 fF for each finger (On state)$$





Comb drive actuator design (C2)

• Capacitance between two metal plates with one stator and one rotor is given as:

$$C = \frac{2n\varepsilon t(y + y_0)}{g}$$

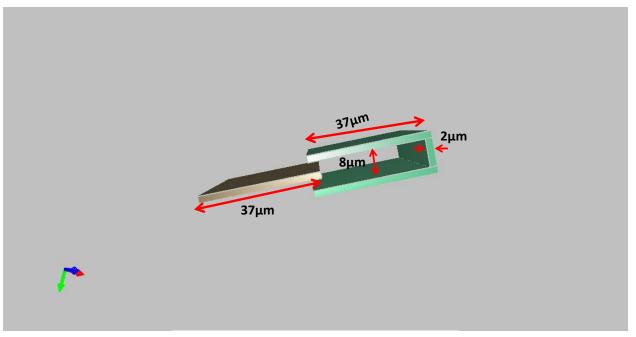
$$71C2 = 130fF$$

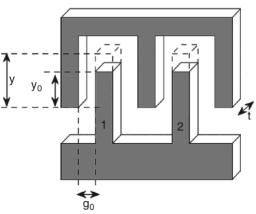
$$C2 = 1.83fF (ON state)$$

• While in OFF state, rotor comb drive makes displacement of 10µm. Which produced capacitance of C2=158fF

$$71C2 = 158fF$$

 $C2 = 2.22fF(OFF state)$



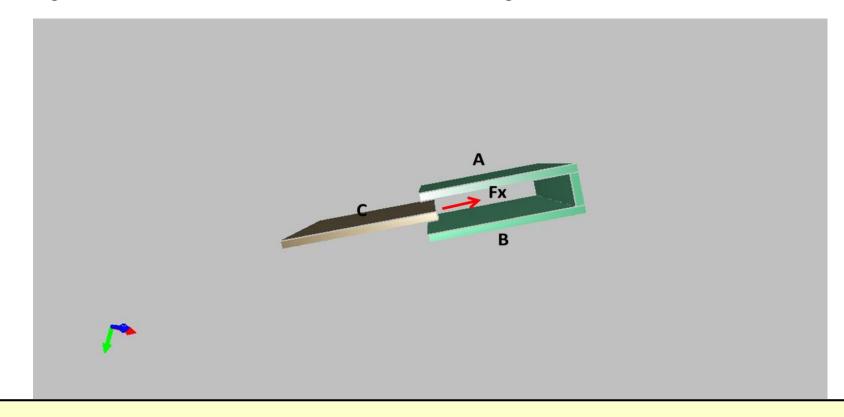




Lateral electrostatic force

$$F_{el} = \frac{1}{2} \frac{\partial CV^2}{\partial y} = \frac{n \in_o tV^2}{g}$$

• To increase the electrostatic force, we can increase actuation voltage (V) or reduce the gap between fingers or increase the number of comb fingers.





Displacement calculation of comb drive

• Under equilibrium condition,

$$F_{el} = F_k = K(y - y_0)$$

So we can calculate the displacement of comb drive as,

$$(y - y_0) = \frac{F_{el}}{K}$$

$$y = y_0 + \frac{n \in U^2}{Kg}$$
, where $K = 2Et(\frac{W}{L})^3$

- After implementing dimensions of comb drive and folded flexure beam, we got the displacement $y=10\mu m$.
- These gives us the capacitance of C1=366fF and C2=158fF that is enough to divert the RF signal produce low impedance path.



Target values obtained

Parameter	ON State	OFF State
C1	43.1fF	366fF
C2	130fF	158.5fF



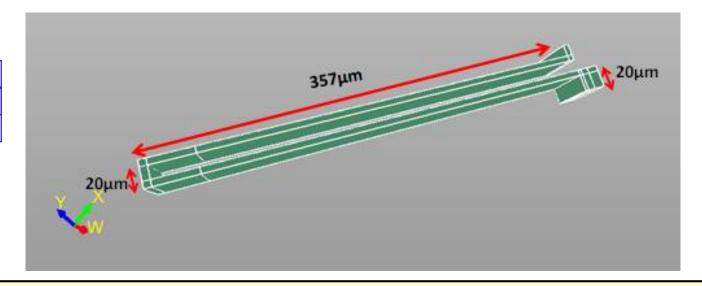
Spring designing parameters

• Stiffness of the spring was measured from the given equation:

$$K = 2Et(\frac{W}{L})^3$$

- To make the spring stiffer, width (W), Young's modulus and thickness of spring should be increased, but stiffer spring will higher restoring force resulting in less displacement.
- We determined a suitable values of all parameter to attain our desired displacement of 10µm, which gives $K = 37.02 \frac{N}{m}$.

Folded Flexure beam	L	357µm
	W	5 μm
	t	40 µm



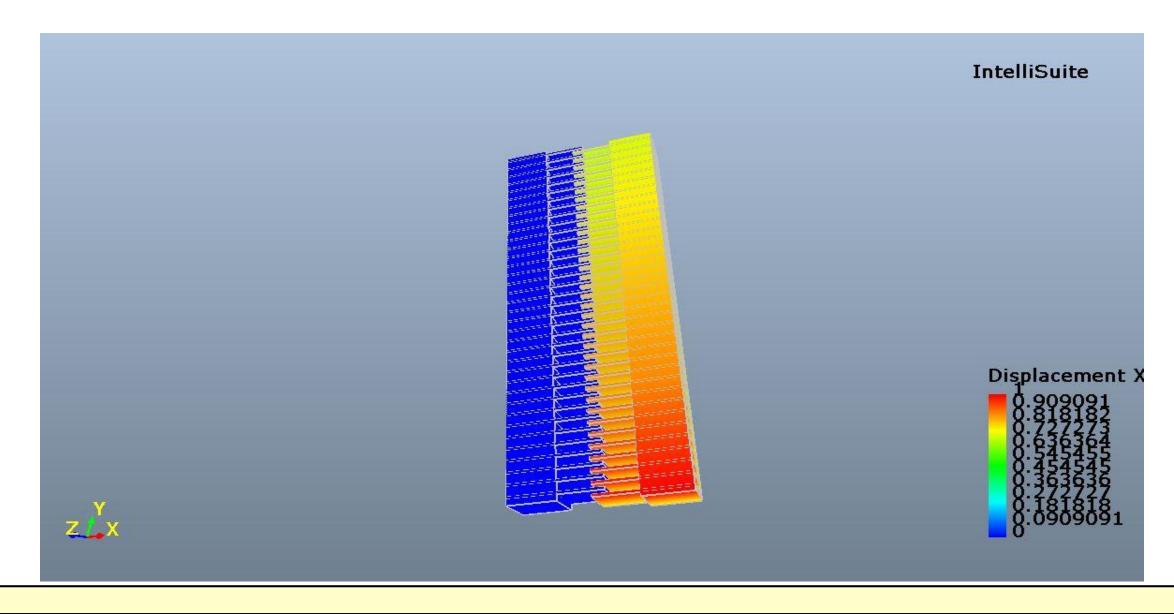


Comparison of different types of springs

Parameters	Fixed –Fixed	Crab leg	Folded flexure beam
Voltage(V)	130	130	130
Displacement (µm)	0.92	1.156	2.85
Force (N)	0.0050	0.0052	0.0056
Capacitance (pF)	326	328	352

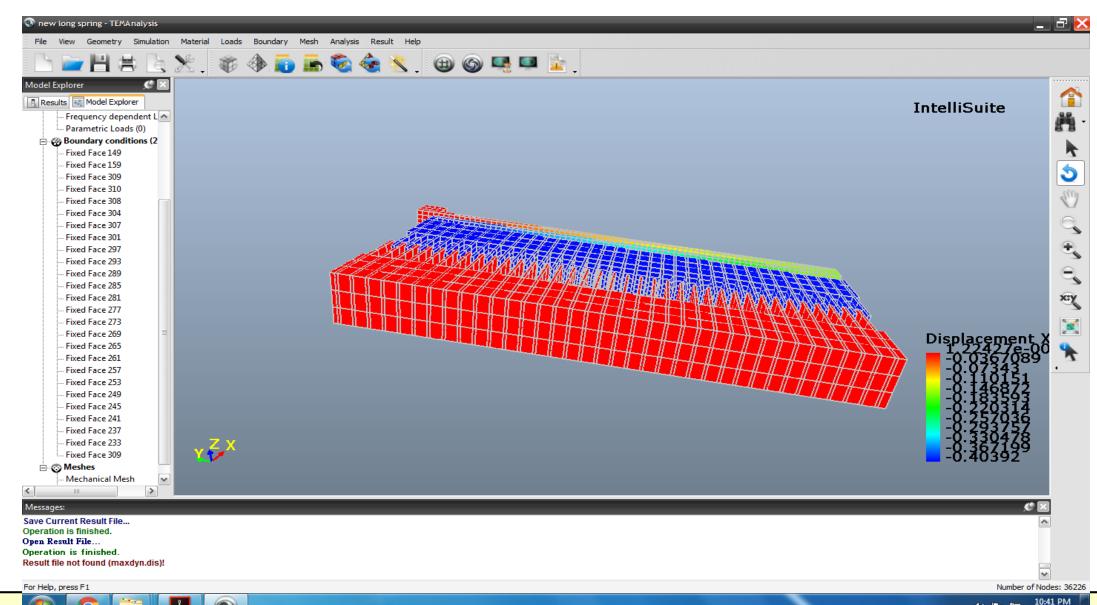


TEM analysis of comb drive without spring



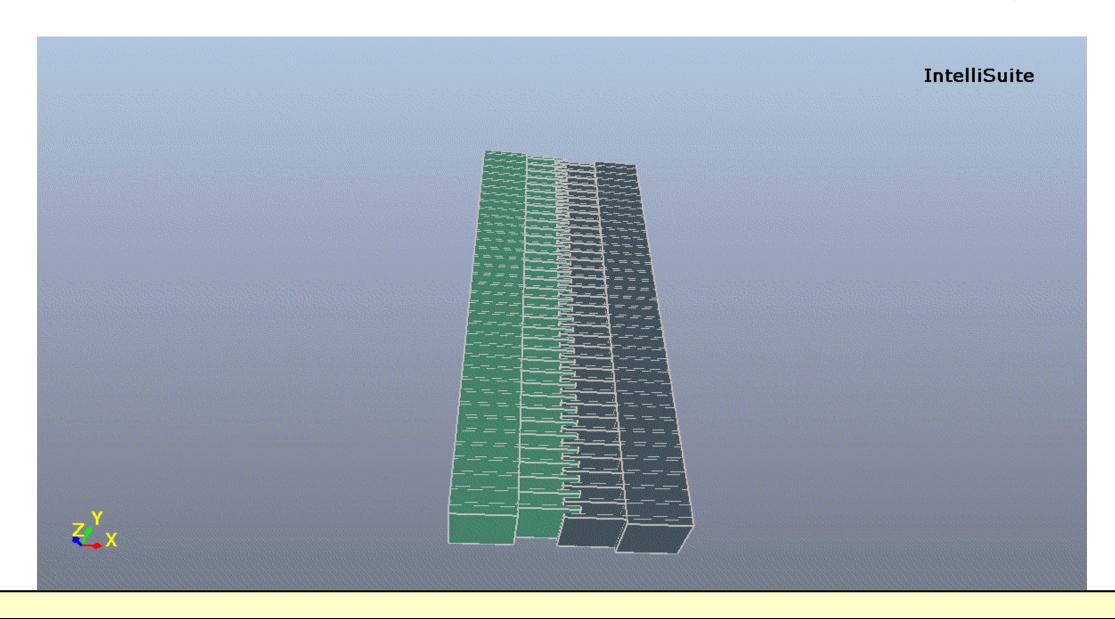


TEM analysis of comb drive with spring



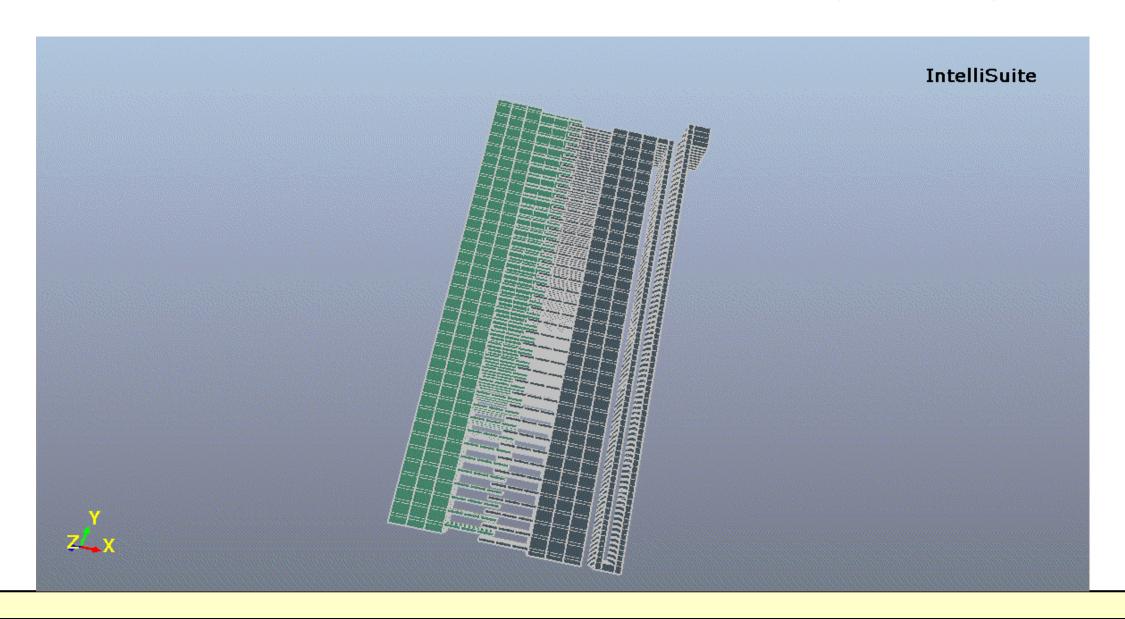


Animation of Comb drive without spring



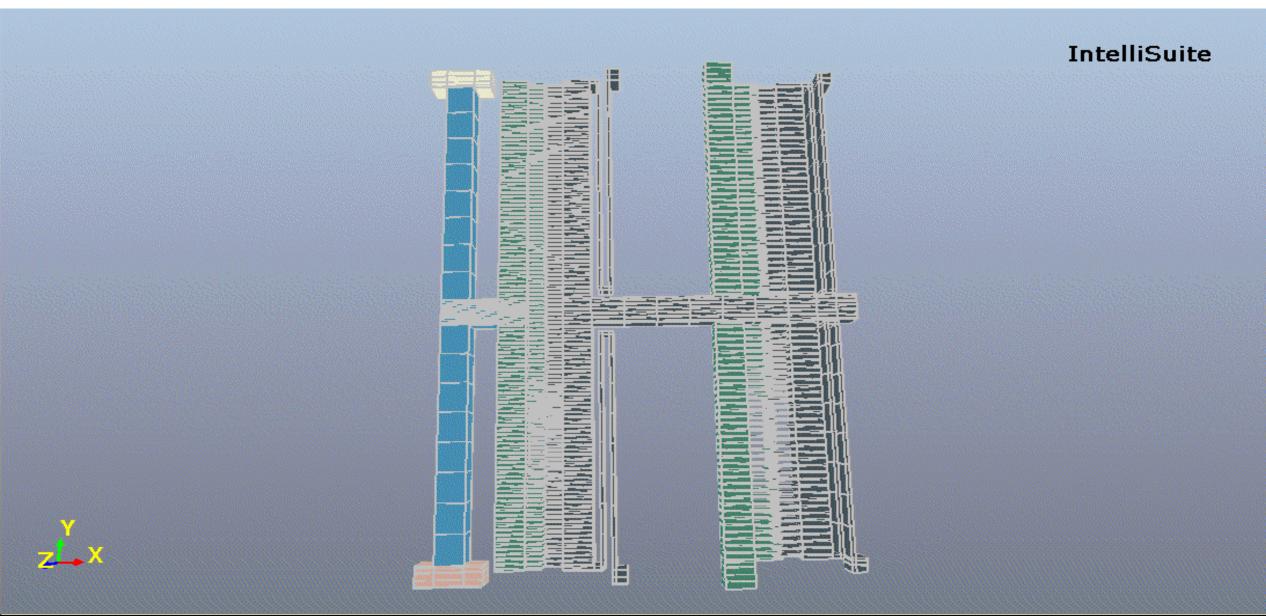


Animation of Comb drive using spring



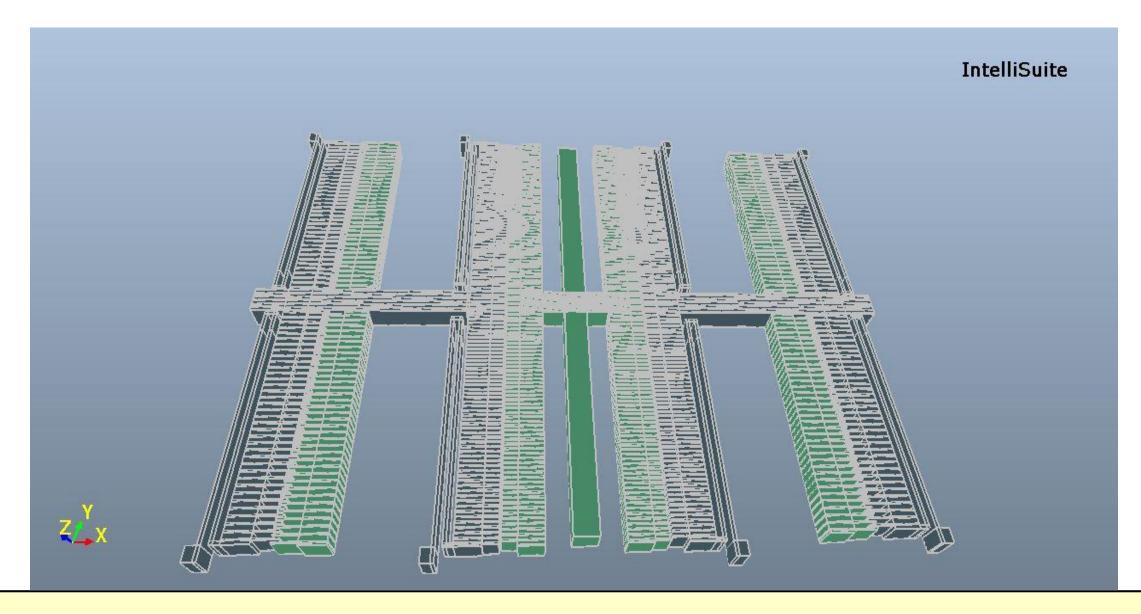


Animation of comb drive actuator



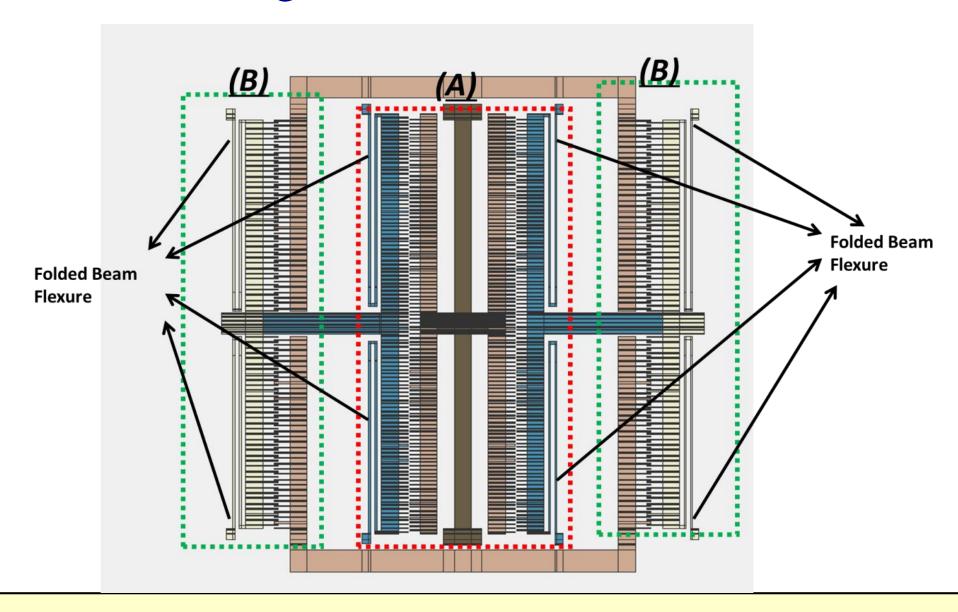


Complete comb drive structure



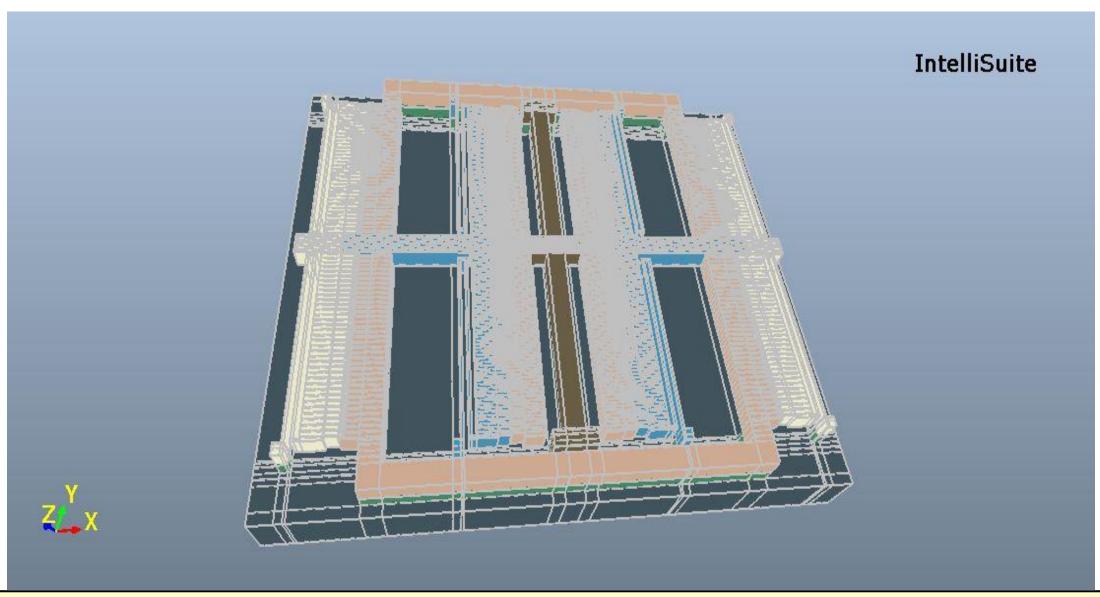


Schematic diagram of non-contact RF switch



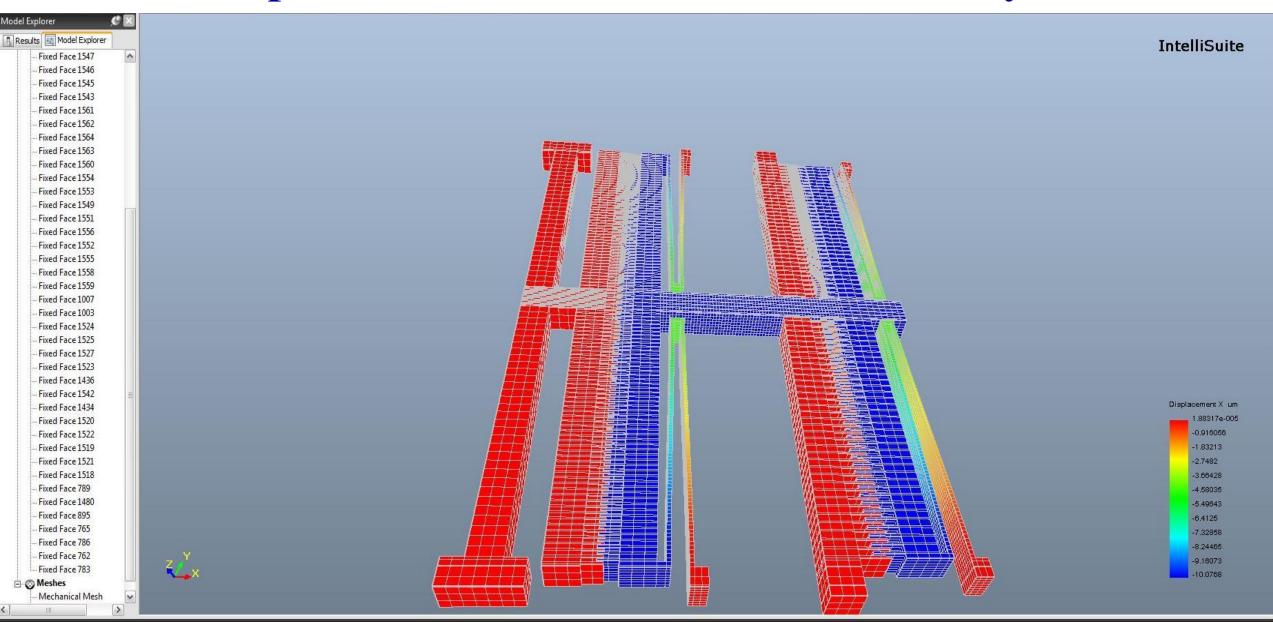


Complete model of switch design





Displacement obtained from TEM analysis





Substrate thickness Calculation

Substrate material (High Resistivity Silicon):

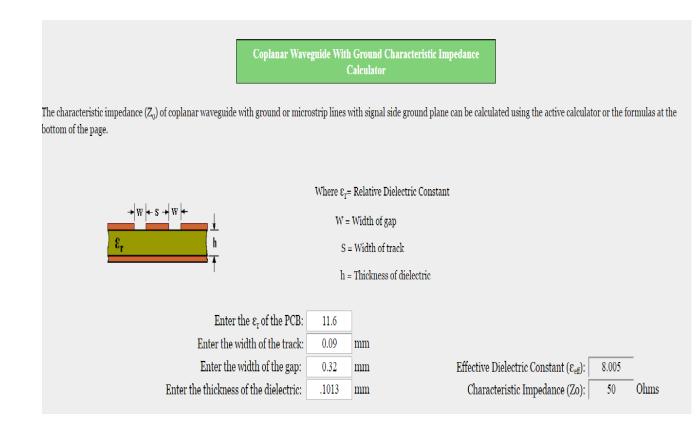
11.6

Width of the gap: 0.32 mm

Width of the signal line: 0.09 mm

Characteristic impedance: 50 Ohm

Thickness of the dielectric: 0.1013 mm



Reference: http://chemandy.com/calculators/coplanar-waveguide-with-ground-calculator.htm



Material Selection

- **High Resistivity Silicon (HRS)**: Normal silicon wafer substrate resistivity ranges typically span from 5 Ω .cm to 30 Ω .cm. But for applications operating at GHz frequency range, the resistivity of silicon wafer should be very high.
- HRS satisfies the requirements of RF applications:
 - 1. Low RF noise
 - 2. Good linearity
 - 3. High breakdown voltage
 - 4. Better thermal conductivity
- At frequencies higher than 1GHz, the skin depth induces high RF losses. So, we choose HRS silicon with resistivity 2000 Ω .cm.



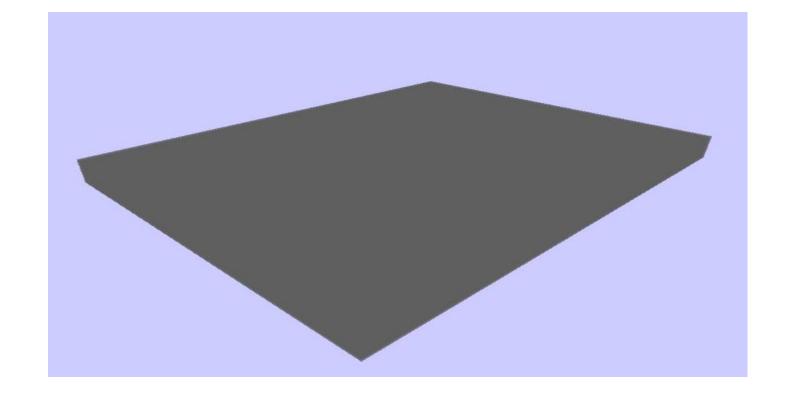
Material Selection

- Silicon nitride and silicon dioxide are used as insulation layers between electrode and the substrate.
- Low stress nitride layer increases the mechanical strength of the released HRS comb structure.
- Tetraethylorthosilicate (TEOS) oxide layer is used as hard mask for Reactive ion etch (RIE).
- Polysilicon is used as sacrificial layer to realize the airgap and also used as a structural material due to its good electrical and mechanical properties.
- Ag, Au, Cu and Al are most conductive metals. We choose Cu as a conducting part of the structure due to its high conductive property and high melting point.



Step 1:

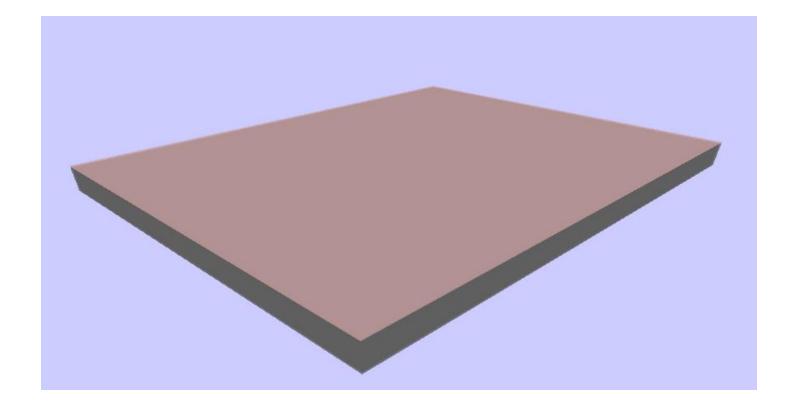
Definition of HRS wafer of thickness (101.3+5 =106.3 μ m) Resistivity: 2000 Ω -cm.





Step 2:

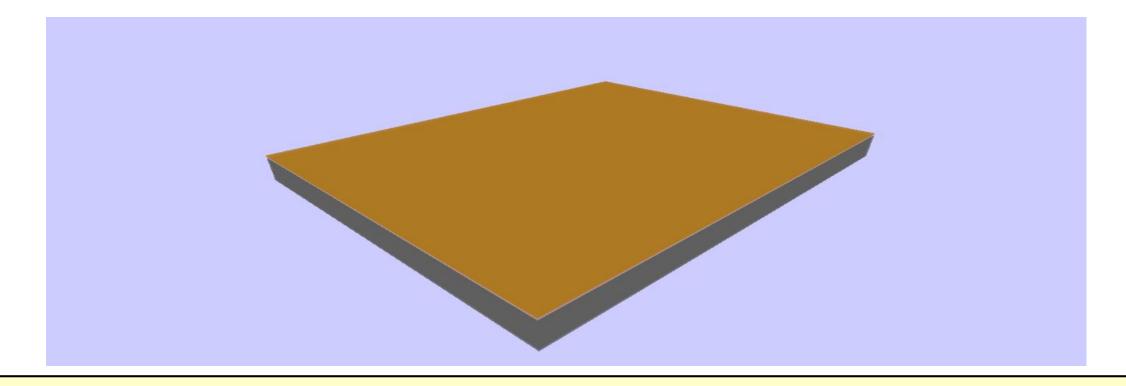
- Deposition of Plasma-enhanced chemical vapor deposition Tetraethylorthosilicate oxide layer.
- Serves as hard mask for Reactive ion etch (RIE).
- Insulation layer between substrate and electrode.





Step 3:

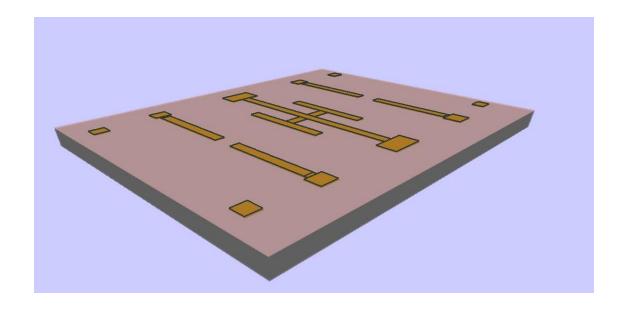
- Deposition of Photoresist (PR-S1800) as a part of Photolithography.
- Lithography in MEMS context is typically the transfer of a pattern to a photosensitive material by exposing to a radiation source.
- A PR is a material which change its physical properties when exposed, so the pattern get transferred to the material exposed.

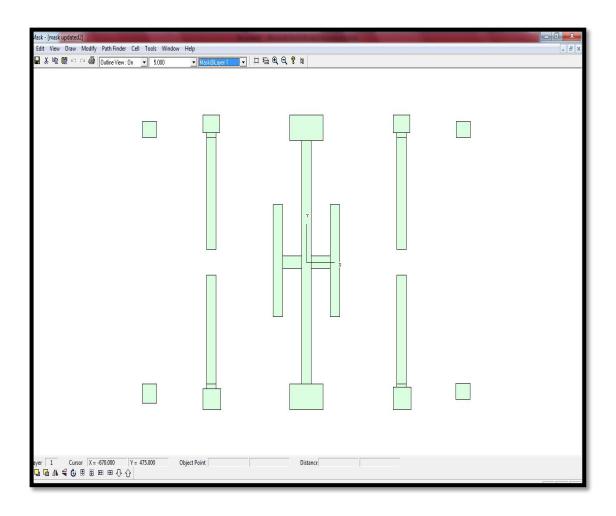




Step 4:

- Exposing the PR layer to the Ultra Violet (UV) radiation.
- Need to specify the layer of the mask file to be patterned.

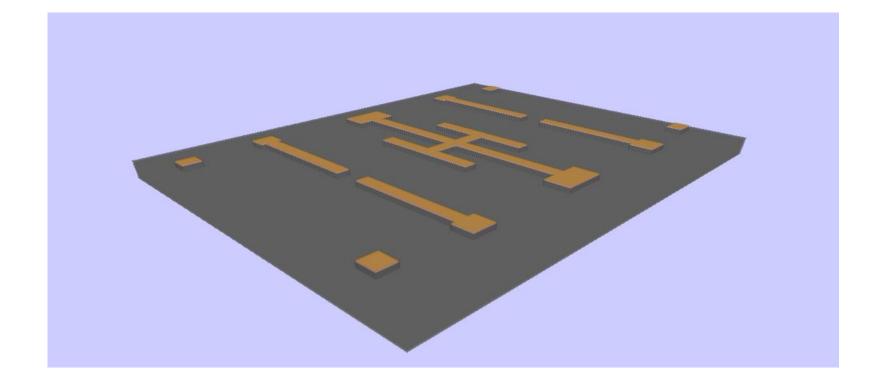






Step 5:

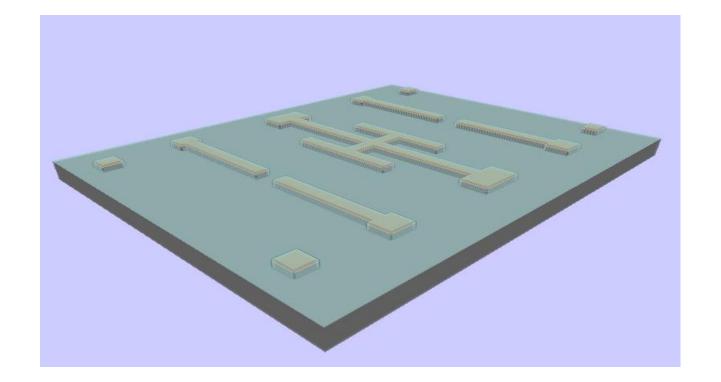
- Etch the HRS silicon, to realize the electrodes using Reactive Ion Etch.
- Partial Etching: When Partial etching is selected, we can specify the value of etching depth(t_etch), in our design t_etch is equal to 5 µm.





Step 6:

- Silicon Nitride (Si3N4) is deposited using PECVD technique.
- Conformal Deposition

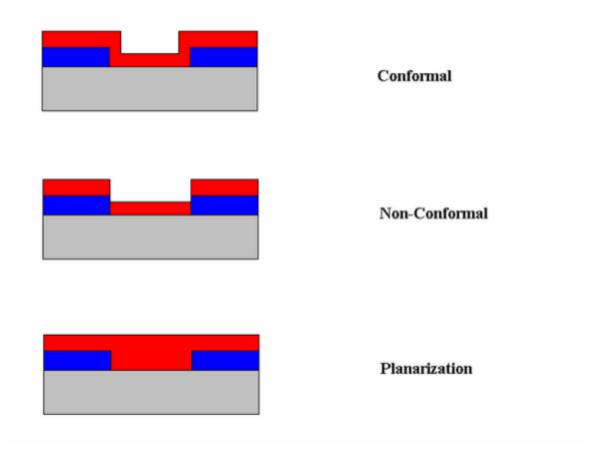




Deposition Techniques

Types of Deposition processes in IntelliFab:

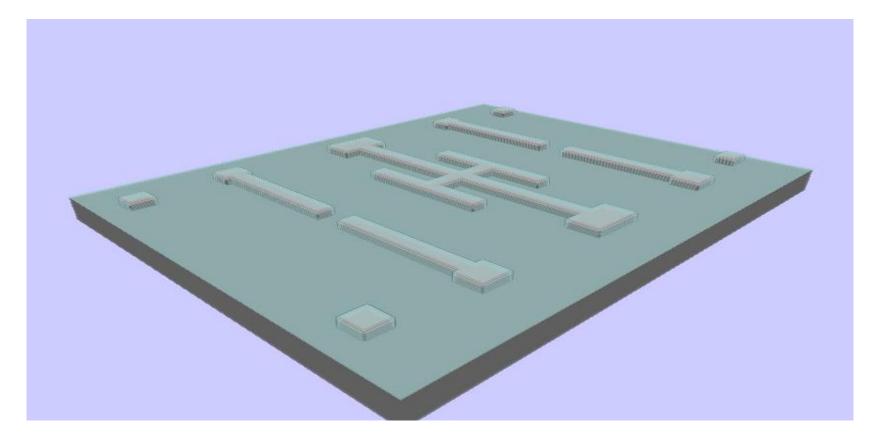
- Conformal: Continuous sidewalls.
- Non-Conformal: Breaking sidewalls.
- Planarization: The top surface of the deposited material will be flat despite the topography of the layers beneath it





Step 7:

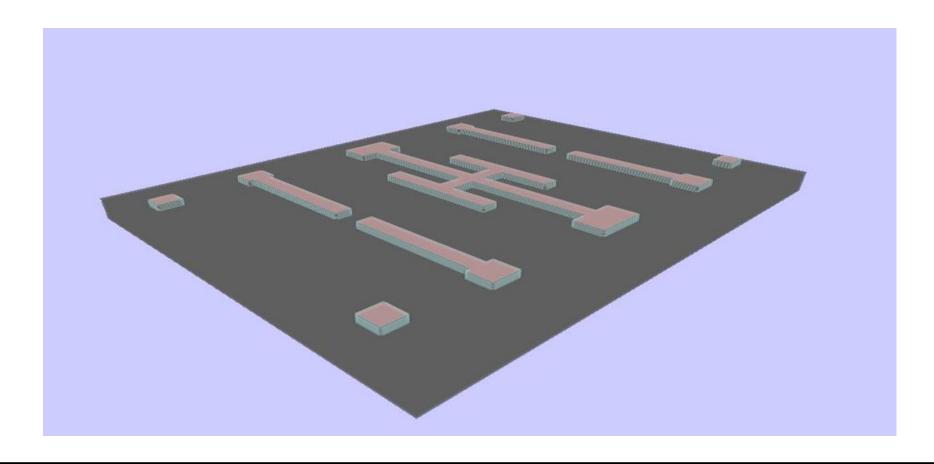
Etch photoresist.





Step 8:

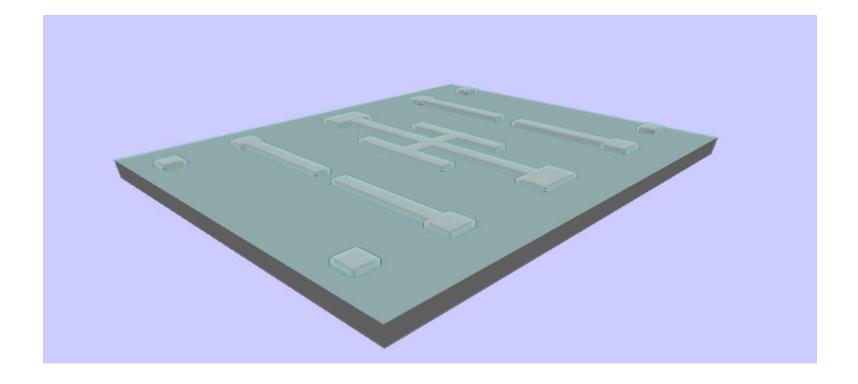
Etch Si₃N₄





Step 9:

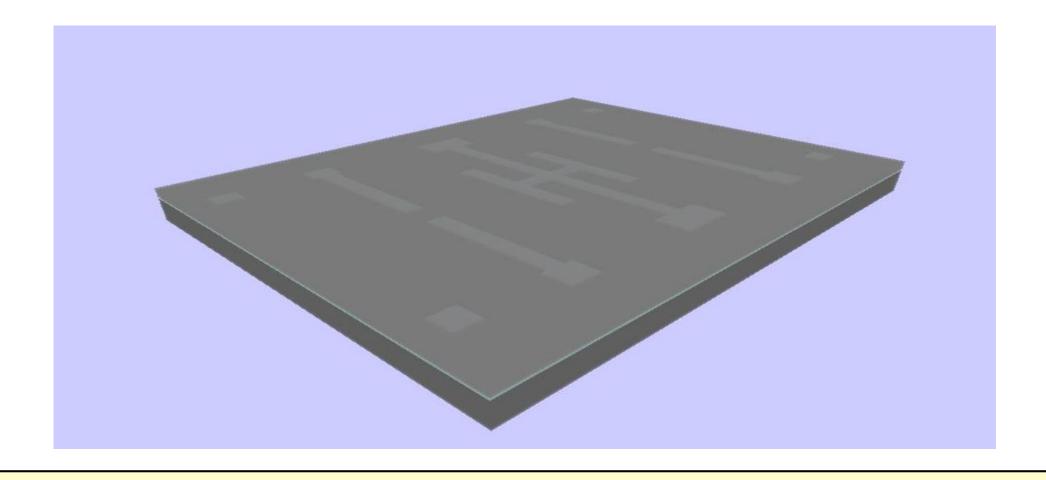
- Deposition of polysilicon.
- Type: Planarization





Step 10:

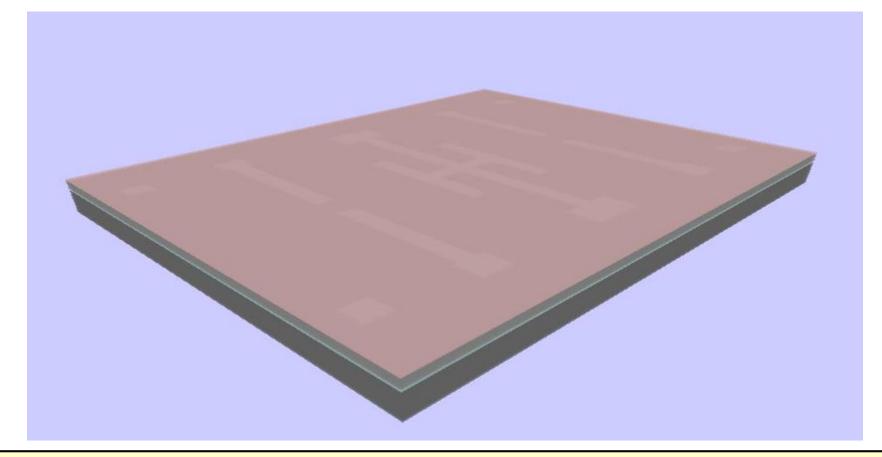
Deposition of Si₃N₄





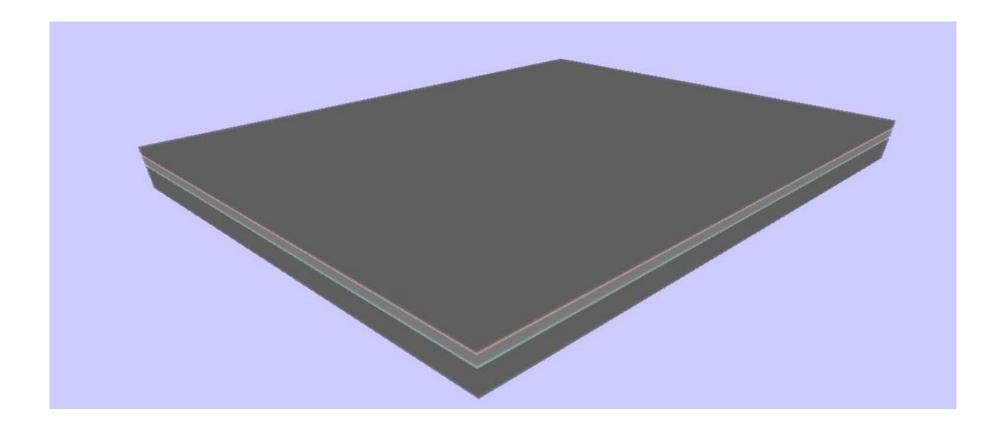
Step 11:

Deposition of Sio2



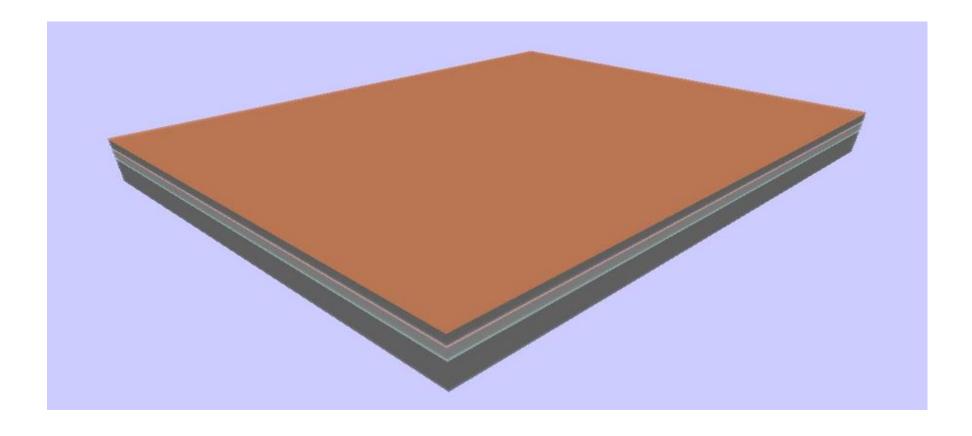


Step 12:
Deposition of HRS





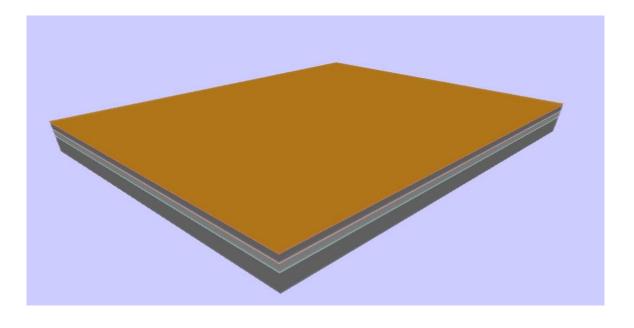
Step 13: Deposition of metal layer

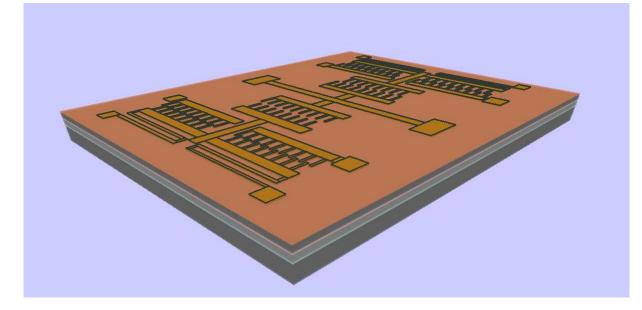




Step 14&15:

Deposition of Photo Resist and exposure of UV radiation, to pattern the mask layer 2.

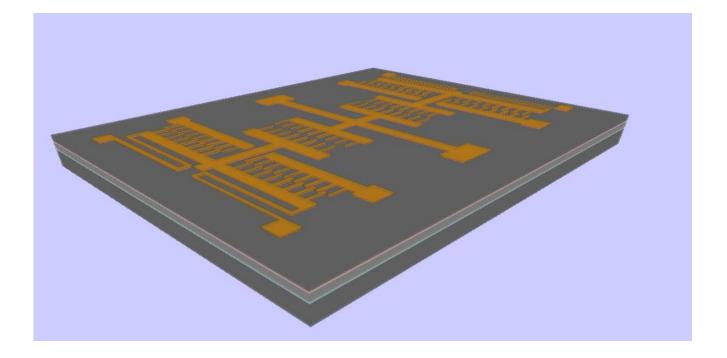






Step 16

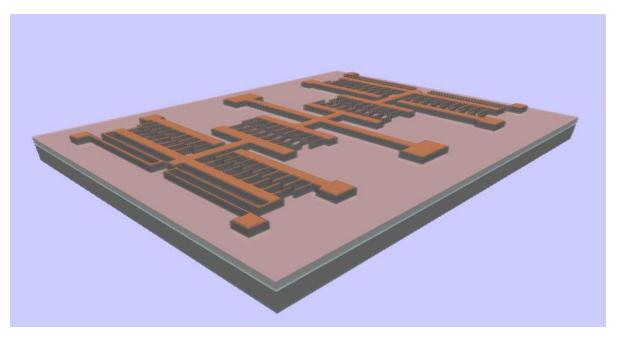
- Before etching Photoresist, etch the copper layer so that a layer of 4 µm is deposited only on the comb structure.
- As whole structure is realized using HRS, which has high resistivity→ Low conductivity, so as to make comb structure conductive, a metal layer is deposited.

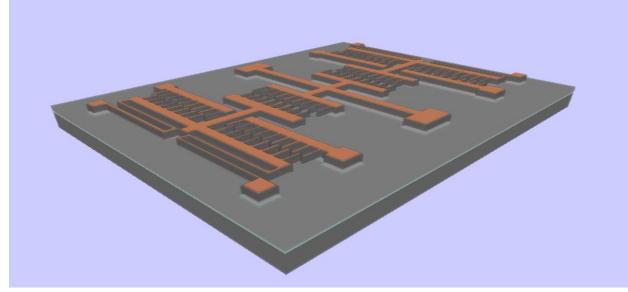




Step 17-step 20:

After that Silicon layer, polysilicon, silicon nitride and polysilicon are etched to realize the pattern transferred from the photolithography of mask layer 2

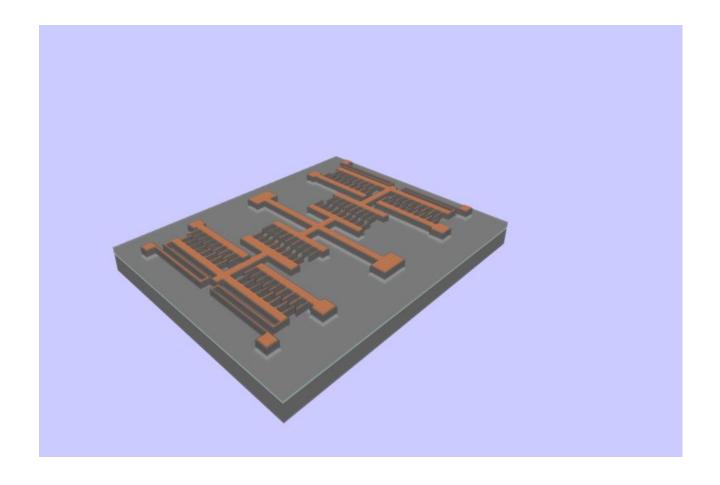






Step 20:

Etching of photoresist





Summary of work done

- We started our project by mathematical modelling of the switch, by considering the conditions to be satisfied during ON and OFF states of switch.
- From analytical model we calculated the capacitance of variable capacitor required to allow (ON state) and Block (OFF state) signal.
- We used these analytical results in Advanced Digital System (ADS) and observe the performance of switch by calculating insertion, isolation and return loss.
- Analytically calculated values are proved to be correct for obtaining good performance.
- Then we mathematically calculated the dimensions of comb drive fingers and spring dimensions to achieve the capacitance value obtained from ADS.
- From mathematical model, displacement of $10\mu m$ is required to obtain the enough capacitance so as to block the signal in OFF state.
- We carried out frequency analysis in Intellisuite TEM module to calculate the displacement and the obtained result is $10.0768 \ \mu m$.
- Our analytical result is in good agreement with Intellisuite simulation result.
- Then we carried out the fabrication process in IntelliFab.



Conclusion

• We compared the designed Non-contact switch parameters with contact RF switch Available in the market (SPDT 24 GHz RF MEMS switch TT1224).

Parameters	Available switch	Designed Switch
Frequency of operation	24GHz	24GHZ
Insertion	0.4dB	0.021 dB
Isolation	20dB	34.228dB
Switch size	3.8mm× 5.1mm	1.1mm × 0.9 mm

- In our design we use 100 volts to generate a displacement of 10 μm, but practically it is not efficient, as power consumption is very high.
- But, voltage can be reduced by inserting additional comb structures to the existing system as shown in [4].
- Non-contact RF switch based on variable capacitance principle, is capable of replacing Contact based RF switch and also offers good performance.



Thank you Any Questions?

